

**Notice of References Cited**

Application/Control No.

09/994,395

Applicant(s)/Patent Under  
Reexamination  
LOPATIN ET AL.

Examiner

Thomas J. Magee

Art Unit

2811

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,399,496 B1 ✓	06-2002	Daniel Charles Edelstein et al.	438/687
	B	US-5,243,222 ✓	09-1993	James M. E. Harper et al.	257/774
	C	US-6,090,710 ✓	07-2000	Panayotis Constantinou Andricacos et al.	438/687
	D	US-6,030,895 ✓	02-2000	Rajiv Vasant Joshi et al.	438/679
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
✓	U	James A. Cunningham, "Improving Copper Interconnects: A Search for Useful Dopants," Semiconductor International, (April. 2000), pp. 1-8.			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.